REMARKS:

Claims 1-5 and 7-18 are currently being considered, of which claims 2, 3, and 5 have been

amended herein and claims 10-18 have been newly added herein.

Applicants and Applicants' attorney thank Examiner Chan for the interview courteously

granted June 13, 2006. The special attention the Examiner paid to the instant application is noted

with appreciation. Items discussed during the interview include: the Office Action dated March 23,

2006; the rejection of claims 1-5 and 7-9; US Pat. No. 6,680,536 (Hattori) and UK Pat. No.

2,383,474 (Walsh); and claim 1 of the subject application.

The Examiner has rejected claims 1-5 and 7-9 under 35 USC 103(a) as obvious over US

Patent No. 6,680,536 (Hattori) in view of UK Patent No. 2,383,474 (Walsh).

Applicants respectfully traverse this rejection, for the following reasons.

On page 3 of the Office Action, the Examiner acknowledges that **Hattori** does not specify

that a second quarter circle arc portion is a little shorter than a first quarter circle arc portion (see

lines 7-9 of claim 1). The Examiner also acknowledges (see page 3 of the Office Action) that

Hattori does not disclose that the distal end of a second quarter arc portion is brought into contact

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with a base plate when a top portion is brought into contact with the measurement objective (see

lines 9-12 of claim 1).

Next, the Examiner relies on Walsh in an attempt to remedy the above-discussed deficiencies

of Hattori.

In particular, the Examiner relies on hook 18 of Walsh.

However, in Walsh, hook 18 does not contact housing 12 and slide, when probe point 16 is

used to take measurements. The hook 18 is used as a hook. Walsh states that "hook 18 may be used

in the conventional manner to secure the probe to a test point or other location in circuit under test"

(page 3, lines 6-9, Walsh).

Thus, in view of the above, Hattori and Walsh, alone or in combination, fail to describe,

teach, or suggest the following features set forth in claim 1: "the top portion of the probe is brought

into contact with an electrode of the measurement objective and elastically deformed and thereby

a distal end of said second quarter arc portion is brought into contact with said base plate and slides,"

in combination with the other claimed features.

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Also, the Examiner has not demonstrated that there exists a motivation to combine/modify

Hattori and Walsh in a manner which arrives at the features set forth in claim 1.

Accordingly, Applicants respectfully submit that the rejection of claim 1 should be

withdrawn.

Additionally, Applicants respectfully submit that the rejection of claims 2-5 and 7-9 should

be withdrawn by virtue of their dependency.

Claims 10-18 have been newly added herein, in order to further clarify the claimed invention.

Claims 2, 3, and 5 have been amended herein to further clarify the claimed invention.

In view of the aforementioned amendments and accompanying remarks, it is respectfully

submitted that all claims currently being considered are in condition for examination.

If, for any reason, it is felt that this application is not now in condition for allowance, the

Examiner is requested to contact the Applicants' undersigned attorney at the telephone number

indicated below to arrange for an interview to expedite the disposition of this case.

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In the event that this paper is not timely filed, the Applicants respectfully petition for an appropriate extension of time. Please charge any fees for such an extension of time and any other fees which may be due now or in the future with respect to this application, to Deposit Account No. 01-2340.

Respectfully submitted,

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